



## Emerging Residue Number System Technologies and Applications

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Deadline for manuscript  
submissions:

**closed (20 December 2022)**

### Message from the Guest Editors

Dear Colleagues,

This Special Issue is aimed at reflecting modern developments in the field of residue number system and its applications, trends, and problems in the development and application of this technology. Submissions researching and generalizing knowledge in the field of the residue number system, from both the theoretical and the practical side, are invited.

Specific topics of interest include, but are not limited to, the following areas:

- Design of high-performance devices using the residue number system
- Challenges and advances of using the residue number system in the field of cryptography
- High-performance digital signal processing methods based on the residue number system
- Error correction and control of data integrity in various applications based on the residue number system
- Residue number system applications in artificial intelligence and machine learning
- Communications and networking using the residue number system





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## Editor-in-Chief

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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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